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SOME ADVANCES IN DOSE MEASUREMENT WITH MOSFET FOR PORTABLE INSTRUMENTATION

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AGENDA

- Research group
- Introduction
- Low cost pMOS as dosimeter
- Procedures of measurement
 - Pulsed biasing (PB)
 - Two currents method (2CM)
 - Three currents method (3CM)
- Portable dosimetry system
- Conclusions
- Acknowledgements

RESEARCH GROUP

- **Interdisciplinary spanish group:**
 - PhDs in Physics
 - PhDs in Electronic Engineering
 - PhD. students in Telecommunications Eng.
 - Several Hospitals in Spain (Granada and Málaga)
- **Main topics in dosimetry:**
 - MOSFET electrical and thermal characterization
 - Monte Carlo simulation of radiation-matter interaction
 - Measurement science
 - Design and testing of electronic instrumentation
- **We offer our experience for collaboration**

INTRODUCTION

- **Scope:** Dose verification systems (DVS) based on MOSFETs mainly for medical use.
- High reliable commercial available DVS:
 - Best medical Canada systems (**BM**)
 - REM Oxford Ltd. (**REM**)
 - One Dose by Sichel Tech.? (**OD**)
- Some little disadvantages
 - Wired sensors for bias purposing (**BM, REM**)
 - Short dose range (**OD**)
 - Expensive RADFETs (**BM, REM, OD**)

INTRODUCTION

- **Our approach**
 - Use of low-cost general-purpose MOSFET as dosimeters
 - Wireless and reusable sensors without bias during irradiation

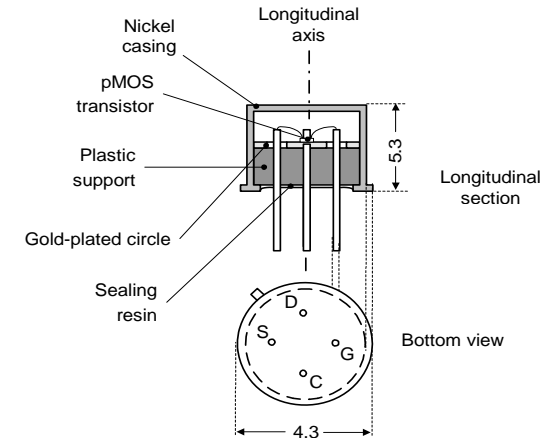
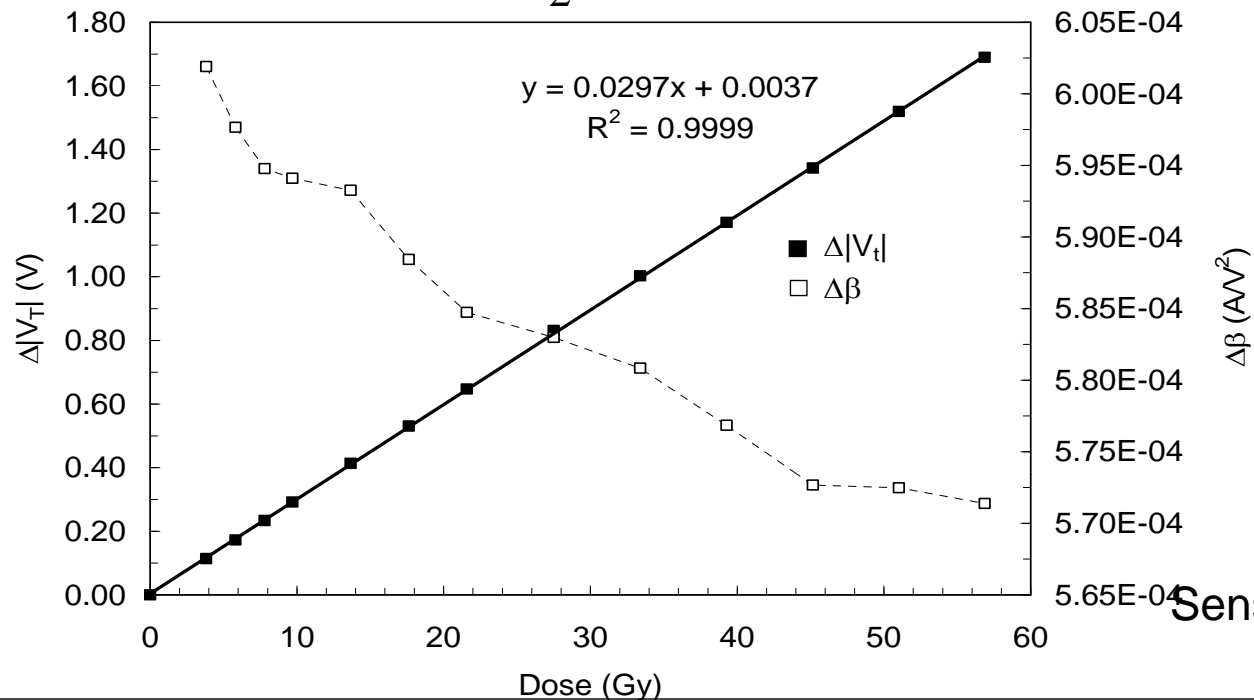
- **Drawbacks of our approach:**
 - Low sensitivity to radiation.
 - Low signal-to-noise ratio (SNR)
 - Low linear range.

- **Objective:** overcoming the above problems

LOW COST pMOS

- **3N163 (Vishay-Siliconix, USA)**
 - Response to radiation from I_D - V_{GS} curves

$$I_D = -\frac{\beta}{2} (|v_{GS}| - |V_t|)^2$$



Sensitivity **30 mV/Gy**

PROCEDURES OF MEASUREMENT

State of the art

- Ionizing radiation creates charge in the oxide: Threshold voltage, V_t , is the dosimetric parameter

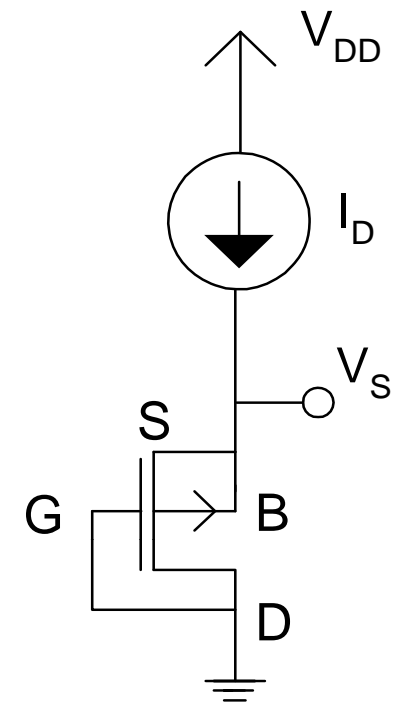
$$\Delta |V_t| > 0$$

$$\Delta \beta < 0$$

- Measurement of V_t at constant drain current ($V_{GD} = 0$). (BM, REM, OD)

$$I_D = -\frac{\beta}{2} (|v_{GS}| - |V_t|)^2$$

$$\beta \approx cte \Rightarrow \Delta |V_t| \approx \Delta |V_S|$$

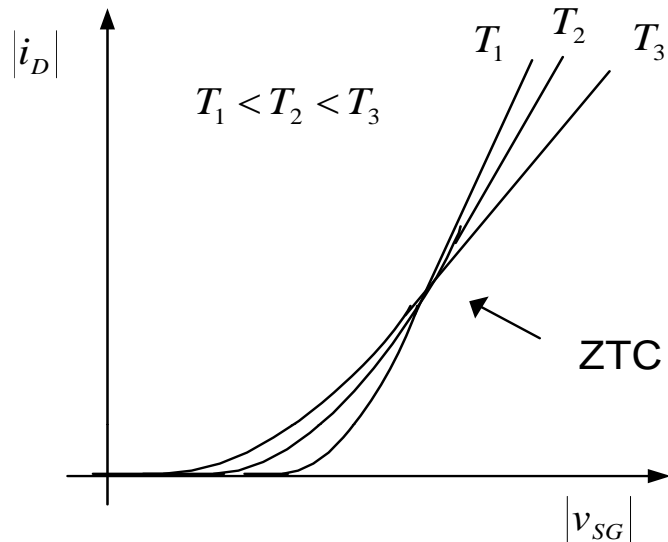


PROCEDURES OF MEASUREMENT

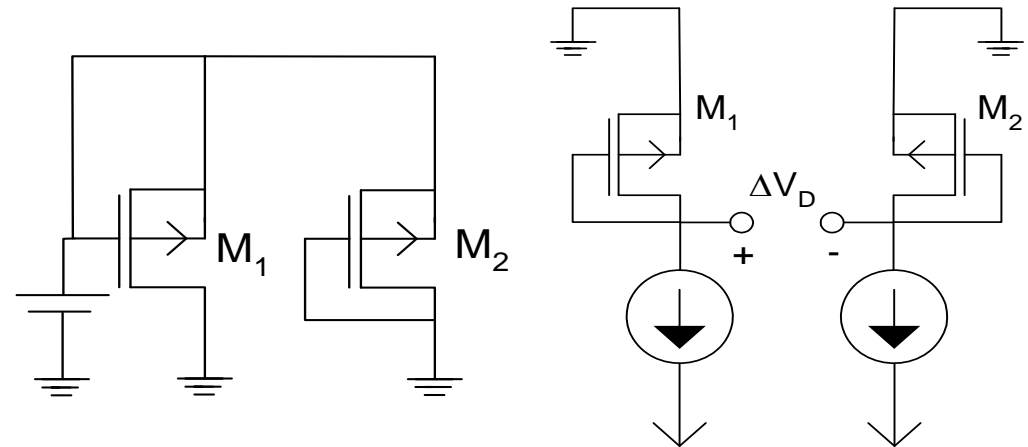
State of the art

■ Thermal compensation techniques

Biasing the pMOS at I_{ZTC}
(REM, OD)



Two identical pMOS with different
sensibilities (BM)



During irradiation

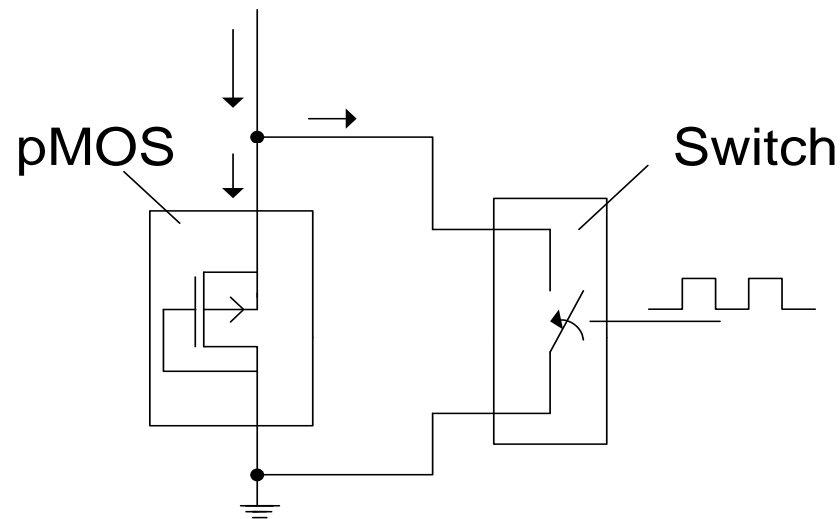
Read-out
configuration

PROCEDURES OF MEASUREMENT

Pulsed biasing (PB)

■ SNR improvement

- Read-time instabilities caused by low frequency noise (LFN) (due to near-interface and interface states)
- How can LFN be reduced? Chopping the drain current as in other experimental techniques (i.e. spectroscopy) and averaging



PROCEDURES OF MEASUREMENT

Two currents method

- **Linear range improvement**

- Reducing $\Delta\beta$ effect in ΔV_t

$$I = \frac{\beta}{2} (V_S - |V_t|)^2$$

- pre- and post-irradiation parameters at constant current I :

$$|V_t| = V_S - \sqrt{\frac{2I}{\beta}} \Rightarrow \left\{ \begin{array}{l} |V_t^{post}| = V_S^{post} - \sqrt{\frac{2I}{\beta^{post}}} \\ |V_t^{pre}| = V_S^{pre} - \sqrt{\frac{2I}{\beta^{pre}}} \end{array} \right\} \Delta|V_t| = \Delta V_S - \sqrt{2I} \left(\sqrt{\frac{1}{\beta^{post}}} - \sqrt{\frac{1}{\beta^{pre}}} \right)$$

PROCEDURES OF MEASUREMENT

Two currents method (TCM)

- **Linear range improvement**

- Using two drain currents for read-out:

$$\Delta|V_t| = \Delta V_{S1} - \sqrt{2I_1} \left(\sqrt{\frac{1}{\beta^{post}}} - \sqrt{\frac{1}{\beta^{pre}}} \right) \quad \Delta|V_t| = \Delta V_{S2} - \sqrt{2I_2} \left(\sqrt{\frac{1}{\beta^{post}}} - \sqrt{\frac{1}{\beta^{pre}}} \right)$$

- Threshold voltage shift without $\Delta\beta$ interference

$$\Delta|V_t| = \Delta V_{S1} + \frac{\Delta V_{S2} - \Delta V_{S1}}{1 - \sqrt{\frac{I_2}{I_1}}}$$

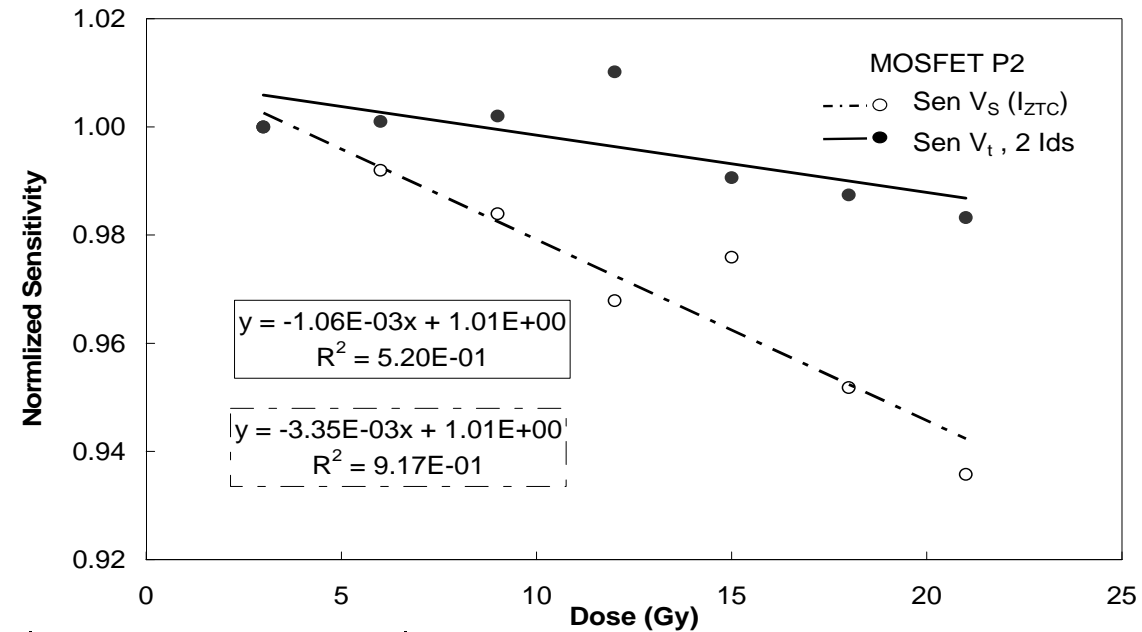
PROCEDURES OF MEASUREMENT

Results (PB+TCM)

■ Linearity improvement

Sensitivity decay coefficient, mean sensitivity and the linear limit (up to 5%).

	DC modes		PB	
	I_{ZTC}	TCM	I_{ZTC}	TCM
m (mV/Gy ²)	-0.153	-0.095	-0.113	-0.057
Mean Sensitivity (mV/Gy)	20.6	19.7	20.0	19.2
Linear Range (Gy)	6.8	10.3	8.8	16.8



20 % reduction of SD

$$\sigma_{V_s}^{DC} = 45.8 \mu V$$

$$\sigma_{V_s}^{PB} = 36.4 \mu V$$

PROCEDURES OF MEASUREMENT

Three currents method (ThCM)

■ Thermal compensation

- Starting hypothesis:

$$\Delta|V_t| = \Delta V_{S1} + \frac{\Delta V_{S2} - \Delta V_{S1}}{1 - \sqrt{\frac{I_2}{I_1}}}$$

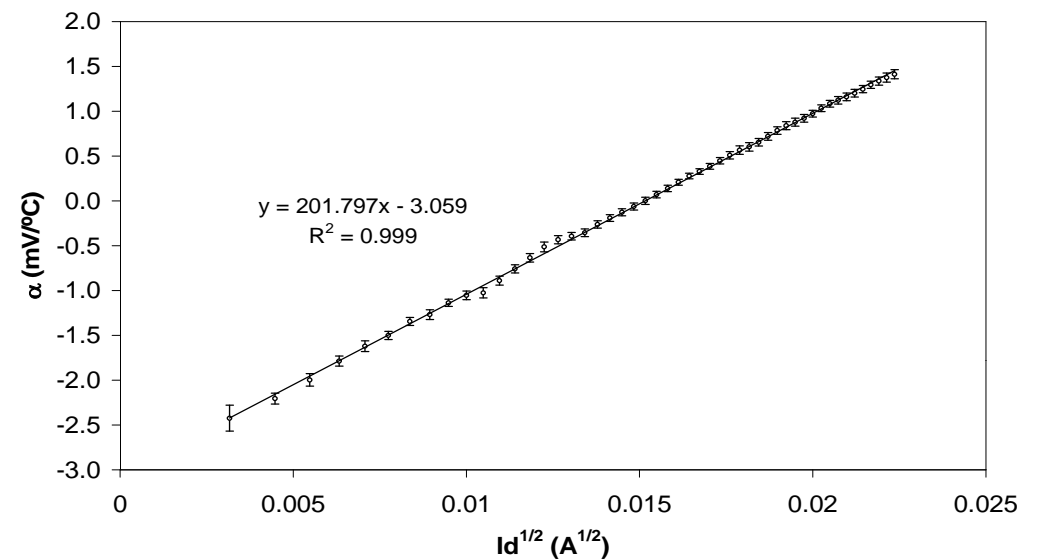
$$\Delta V_{S1}(T) = \Delta V_{S1}^0 + \alpha_1 \Delta T$$

$$\Delta V_{S2}(T) = \Delta V_{S2}^0 + \alpha_2 \Delta T$$

$$\Delta|V_t|(T) = \Delta|V_t|^0 + \alpha_{|V_t|}(T - T_0)$$

- Experimentally verified

$$\Rightarrow \alpha_i = \alpha_{|V_t|} \left(1 - \sqrt{\frac{I}{I_{ZTC}}} \right)$$



PROCEDURES OF MEASUREMENT

Three currents method (ThCM)

■ Thermal compensation

- $\Delta|V_t|$ thermal compensated

$$\Delta|V_t| = \Delta V_{S1}^0 + \frac{\Delta V_{S2}^0 - \Delta V_{S1}^0}{1 - \sqrt{\frac{I_2}{I_1}}}$$

- Additional current: I_3

$$\Rightarrow \Delta V_{S1}^0 = \Delta V_{S1} + (\Delta V_{S3} - \Delta V_{S1}) \frac{\sqrt{I_1} - \sqrt{I_{ZTC}}}{\sqrt{I_1} - \sqrt{I_3}}$$

$$\Delta V_{S2}^0 = \Delta V_{S2} + (\Delta V_{S3} - \Delta V_{S2}) \frac{\sqrt{I_2} - \sqrt{I_{ZTC}}}{\sqrt{I_2} - \sqrt{I_3}}$$

- Simplification $I_1 = I_{ZTC}$

$$\Delta|V_t| = \Delta V_{S,ZTC} + \frac{\Delta V_{S2}^0 - \Delta V_{S,ZTC}}{1 - \sqrt{\frac{I_2}{I_{ZTC}}}}$$

PROCEDURES OF MEASUREMENT

Results (ThCM)

■ Thermal compensation:

- Reduction in a factor of **50** in the thermal drift

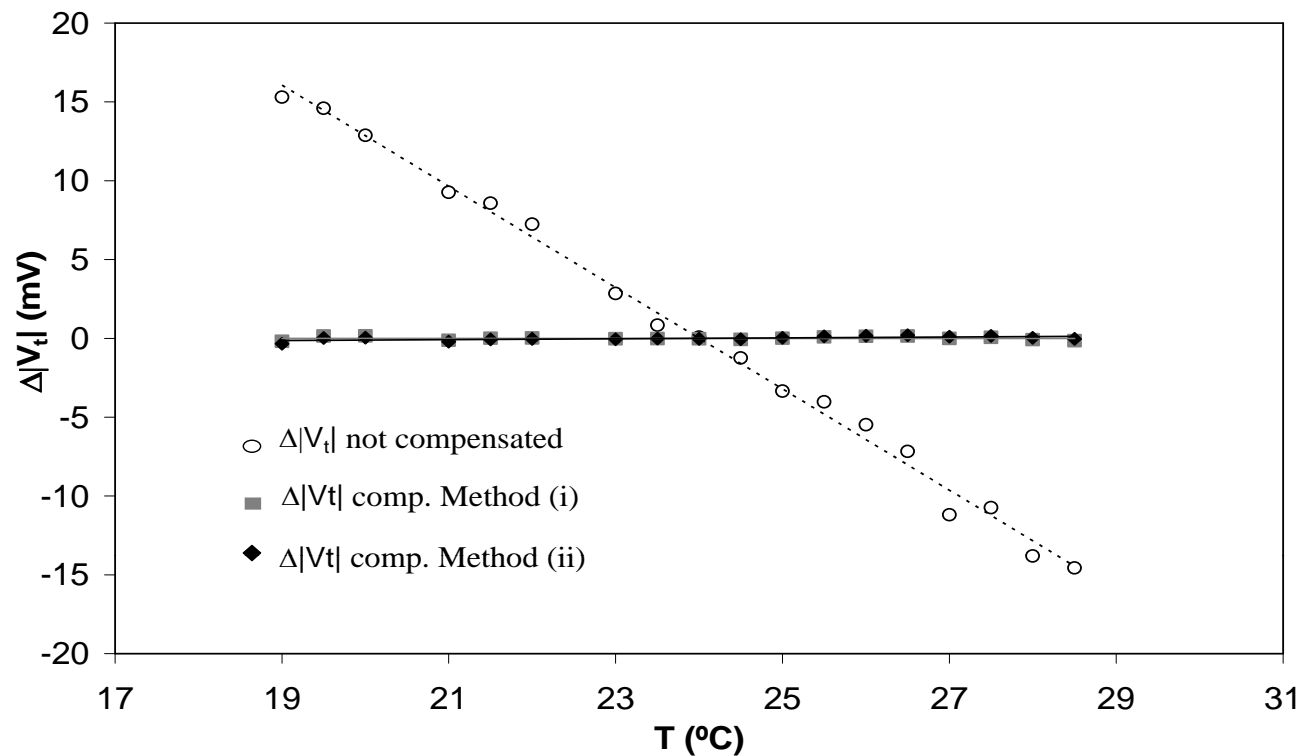
$$I_2 = 30 \mu A$$

$$I_3 = 120 \mu A$$

$$I_{ZTC} = 225 \mu A$$

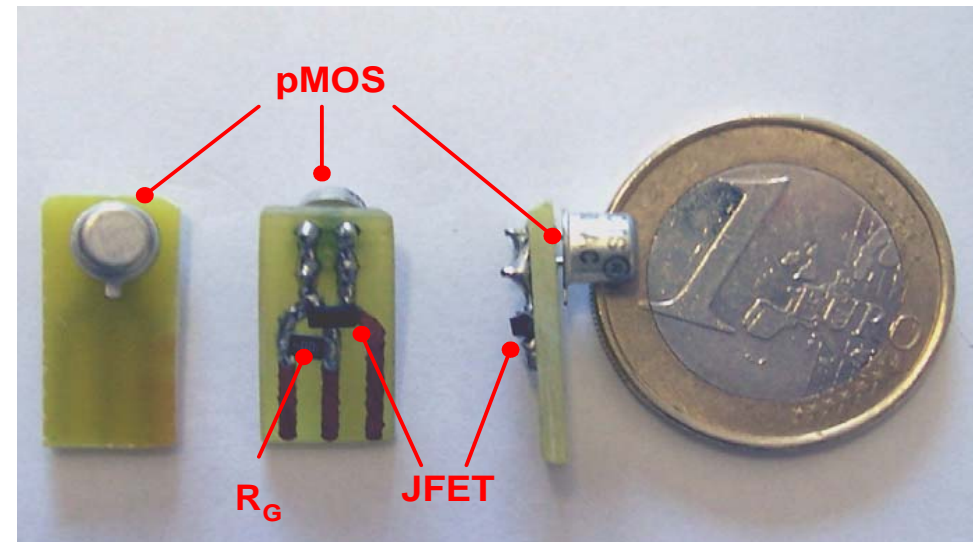
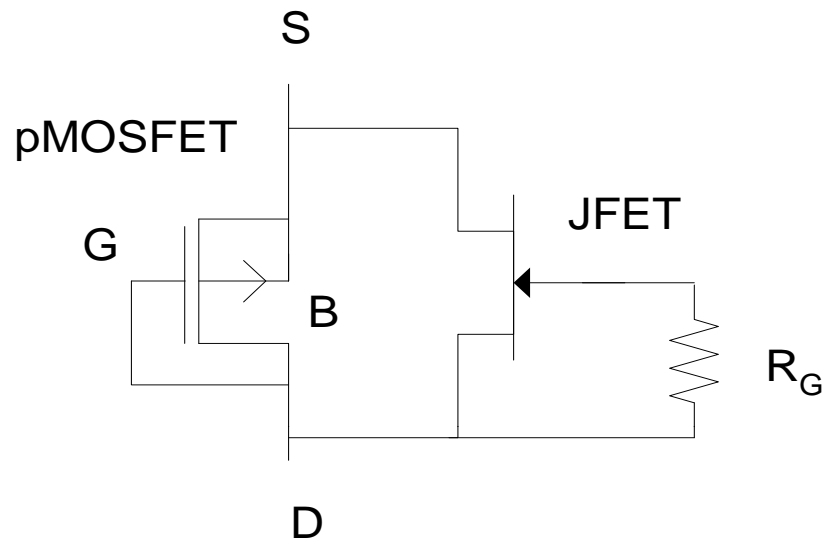
Compensated

$$\frac{\Delta V_t}{\Delta T} < 70 \mu V / ^\circ C$$



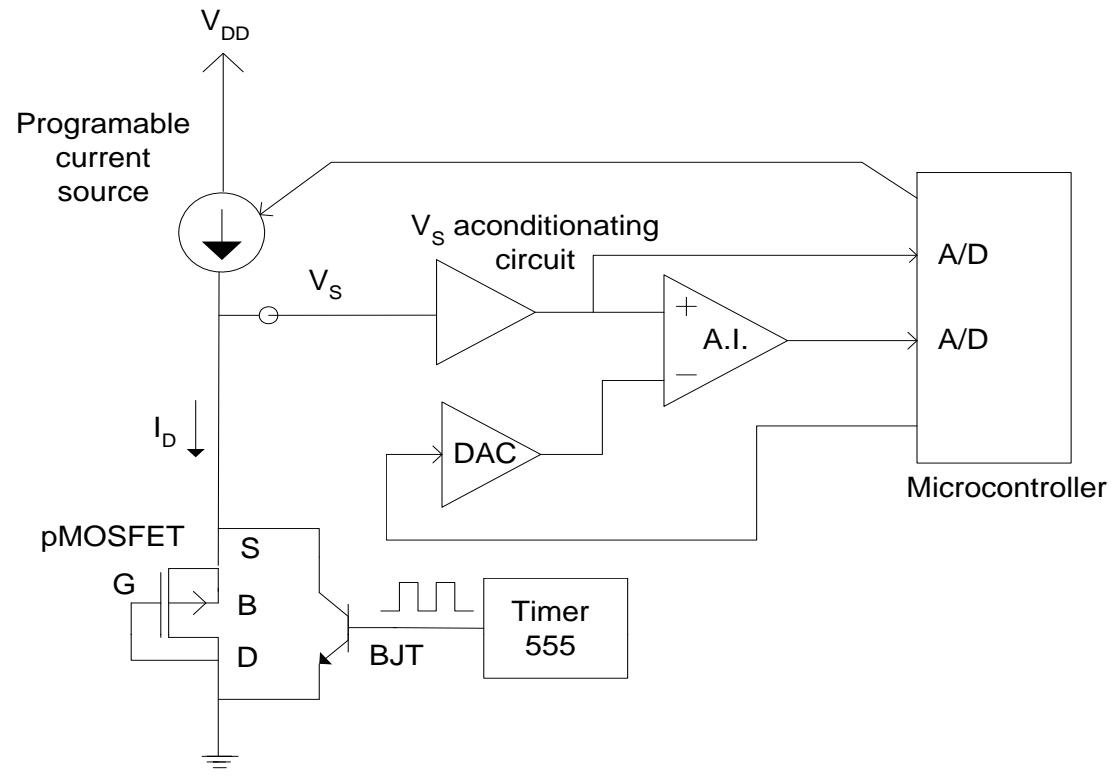
■ Sensor Module

- JFET as a switch (shortcircuited during irradiation and storage and open during read-out)



PORTABLE DOSIMETRY SYSTEM

■ Reader Unit



PORTABLE DOSIMETRY SYSTEM

■ Dose measurement process

- Zeroing:
 - Measurement and storage of pre-irradiation V_S at the two (three) drain currents
- Irradiation
- Wait for short-term fading (120 -180 s)
- Dose measurement
 - Read the pre-irradiation values
 - Measurement and storage the post-irradiation V_S at the two (three) currents
 - Dose calculation (calibration is required)

PORTABLE DOSIMETRY SYSTEM

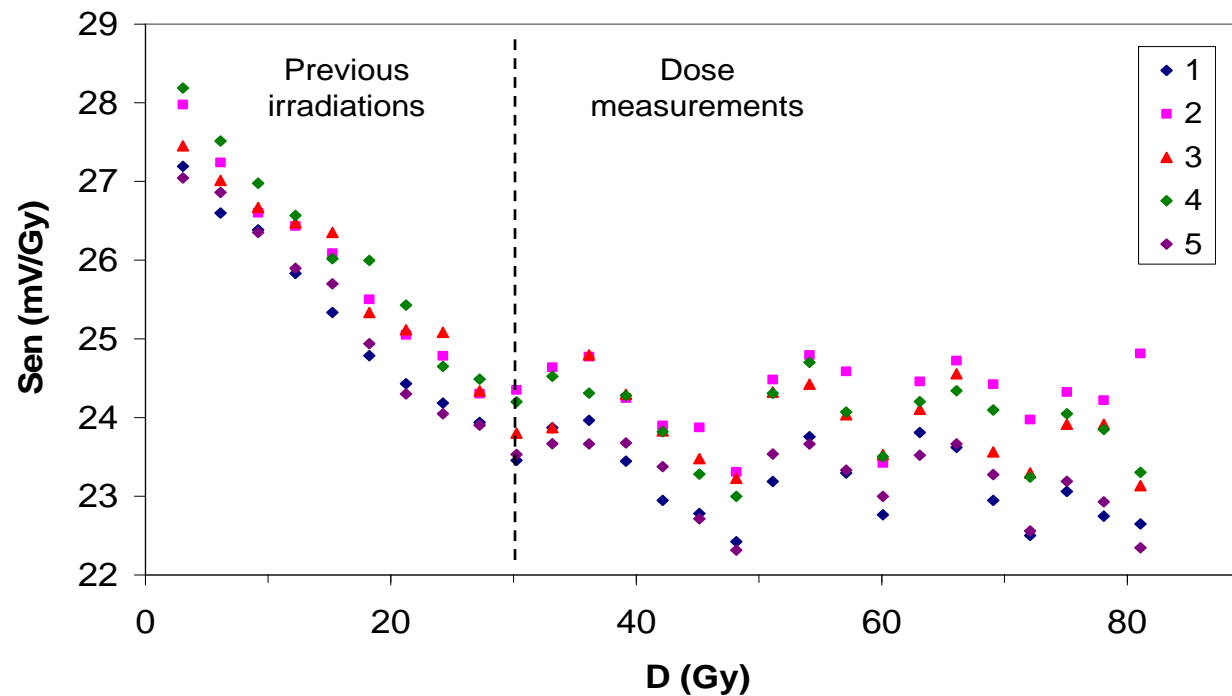
■ Irradiation conditions

- Theratron-780 with a ^{60}Co source and a field of 25 x 25 cm²
- MOSFETs, in electronic equilibrium condition, located at 80 cm of the isocentre



PORTABLE DOSIMETRY SYSTEM Results

■ Sensitivity per session



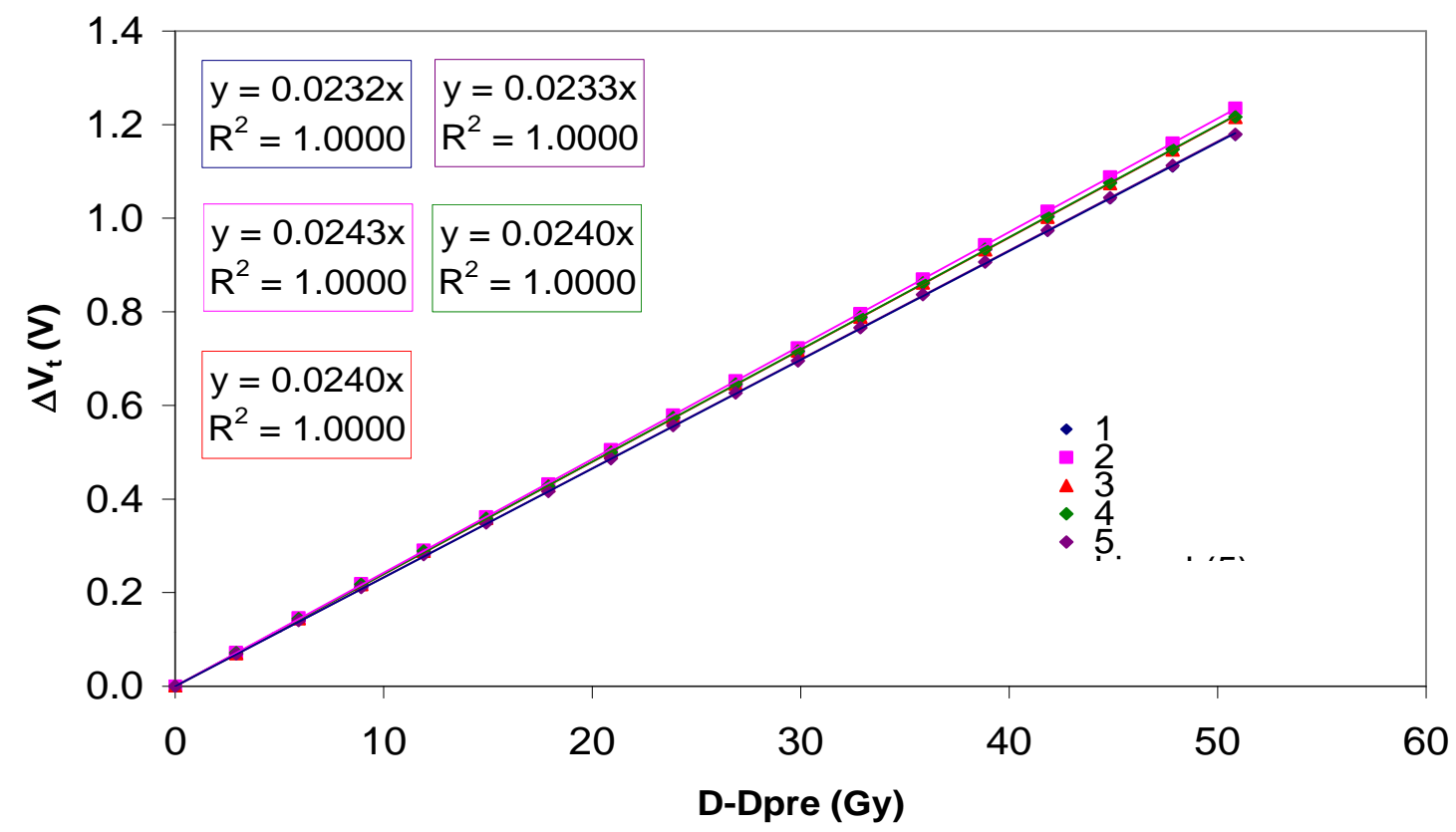
$$S = \frac{\Delta |V_T|}{D}$$

A pre-irradiation of 30 Gy is required for reproducibility of S

PORTABLE DOSIMETRY SYSTEM Results

■ Radiation response

Dpre=30 Gy



PORTABLE DOSIMETRY SYSTEM

Technical specifications

Temperature range	10 – 40 °C
Resolution	1 cGy
Accuracy	± 3 %
Linear range	15 Gy > 80 Gy*
Thermal drift	< 3mGy/°C
Delay after irradiation	2 – 3 minutes

* with recalibrations every 15 Gy

CONCLUSIONS

- Procedures of dose measurement for linearity and SNR improvement and thermal drift reduction
- Portable dosimetry system based on commercial and standard MOSFET sensor
 - Wireless sensor
 - Reusable sensor (up to 80 Gy with recalibration each 15 Gy)
 - Thermal compensation without additional devices (3 mGy/°C)

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